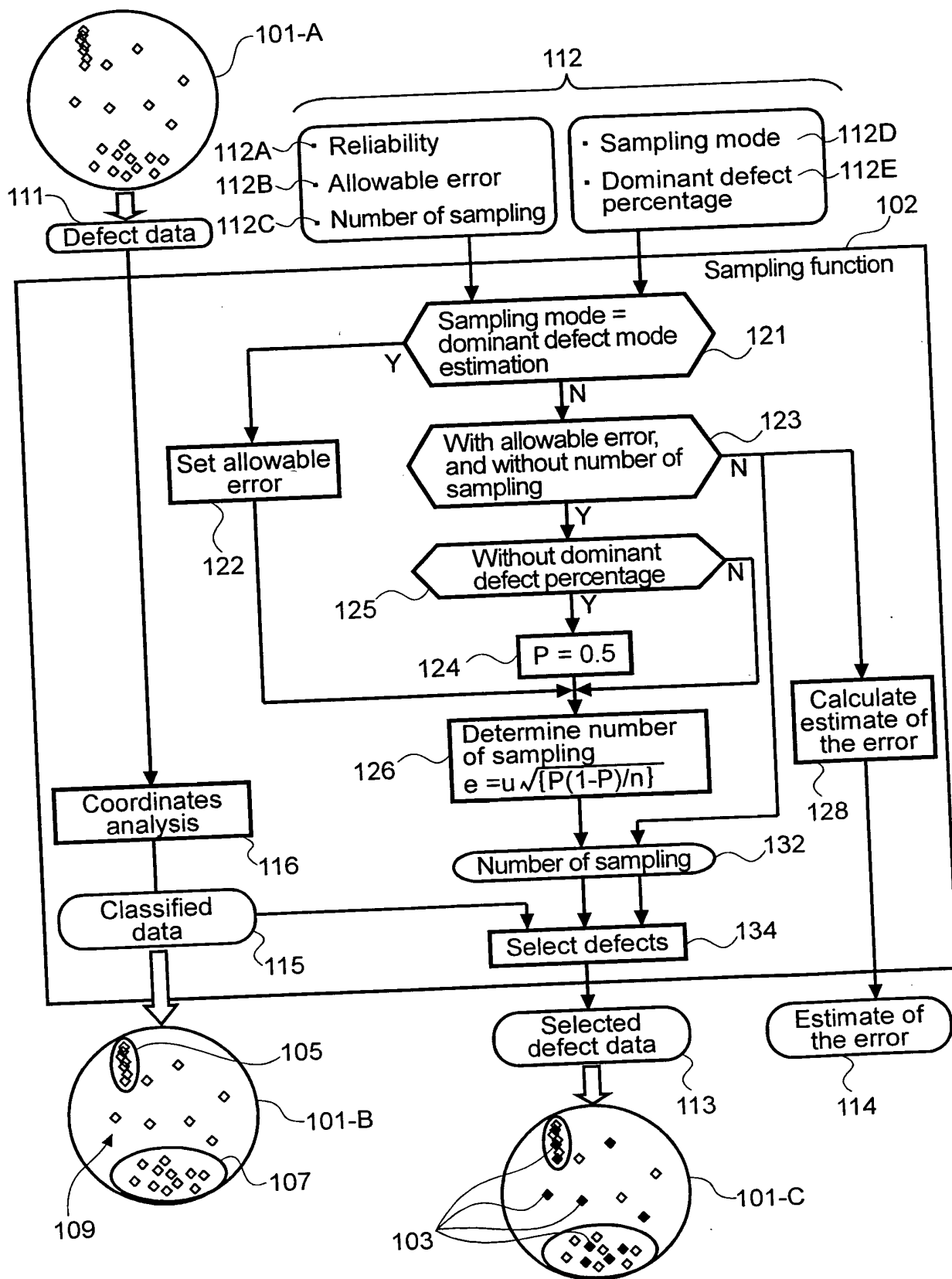


FIG.1



202

Reliability	U
0.80	1.28
0.90	1.65
0.98	2.33
...	...

FIG. 3

[illegible]

FIG.4

Reliability

%

Whole wafer

Classified Regions

High Density

Dense

Sparse

Sampling mode

D.D. %

error %

Samples

OK

CANCEL

FIG. 5

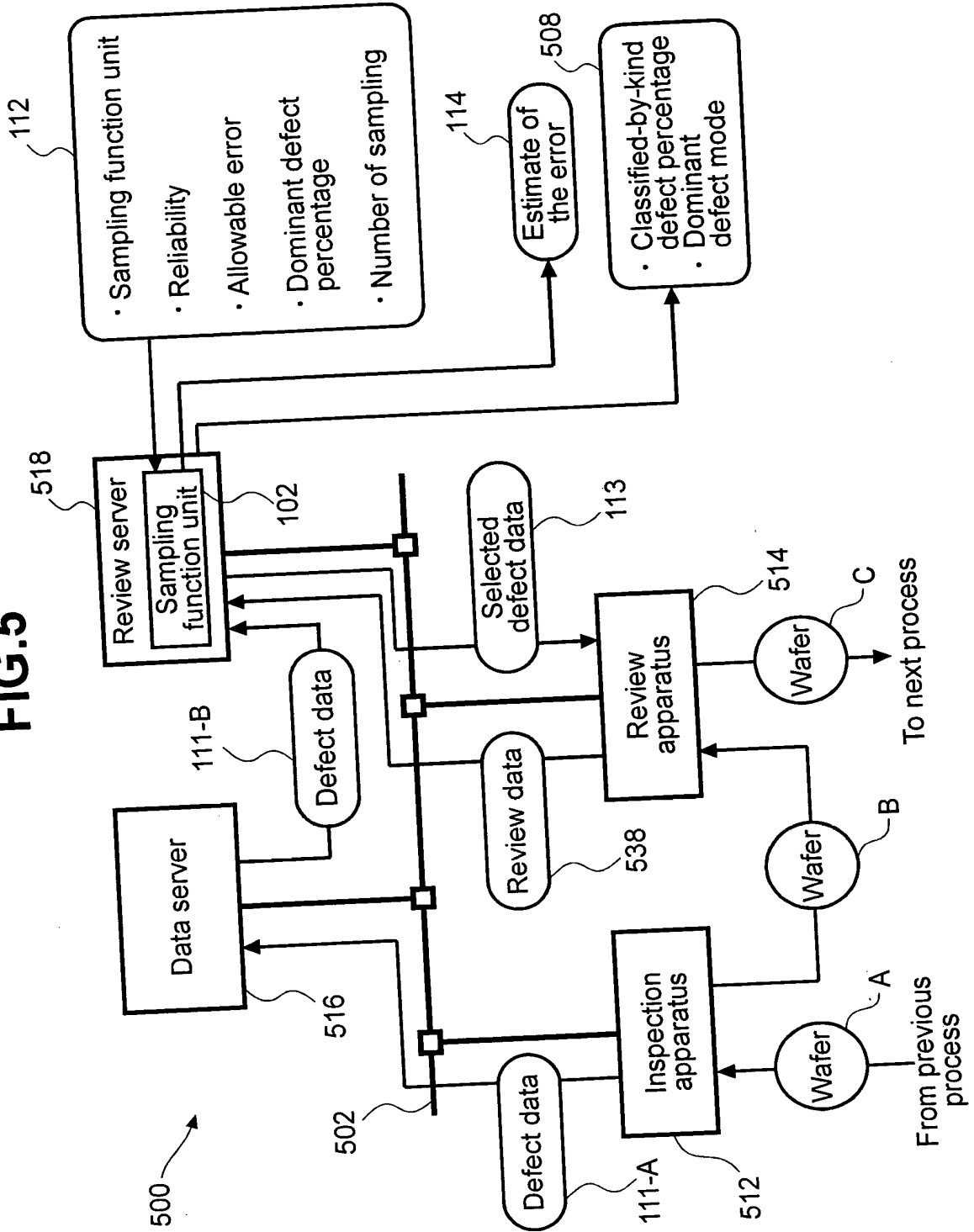


FIG. 6

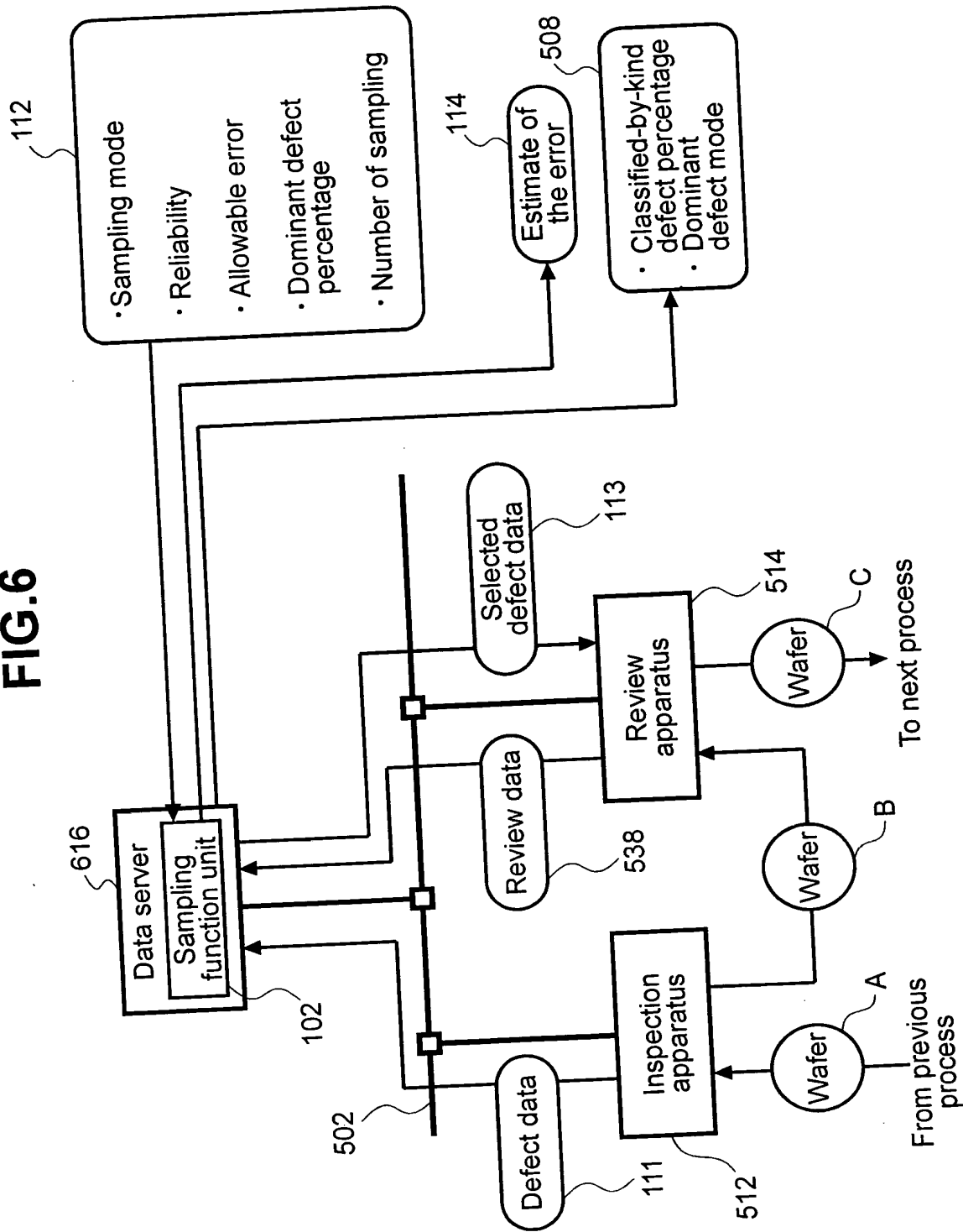


FIG. 7

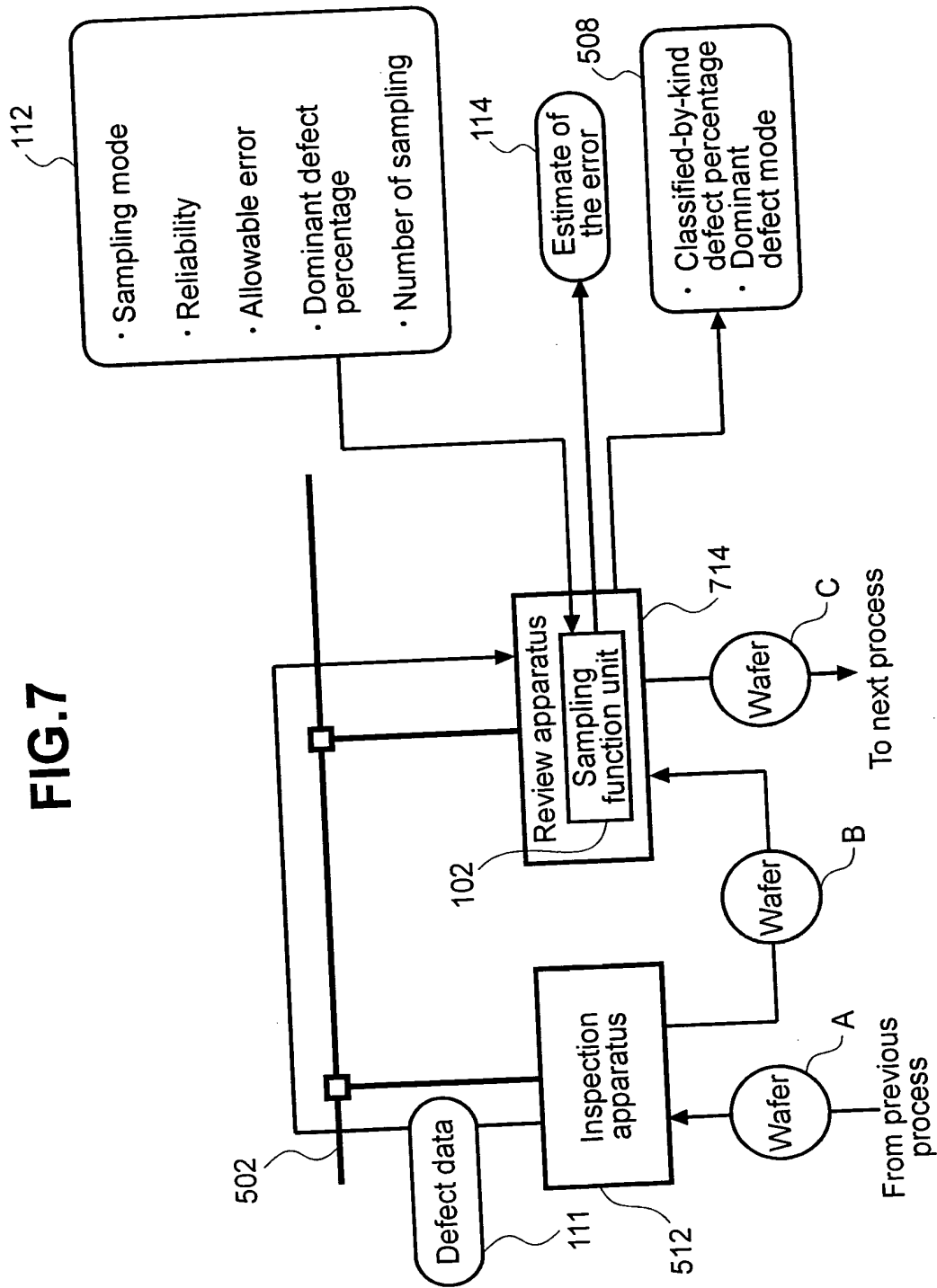


FIG. 8

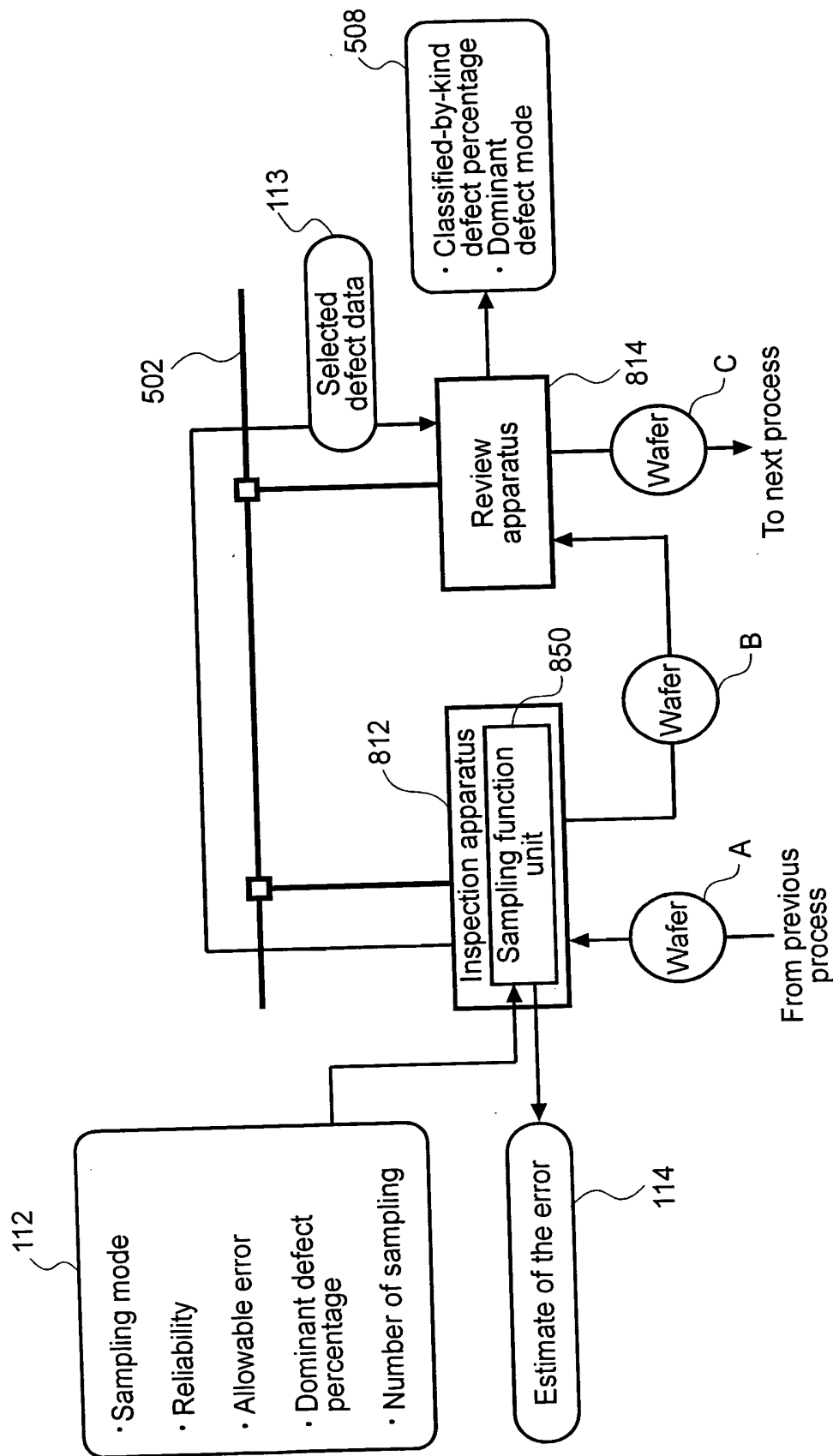
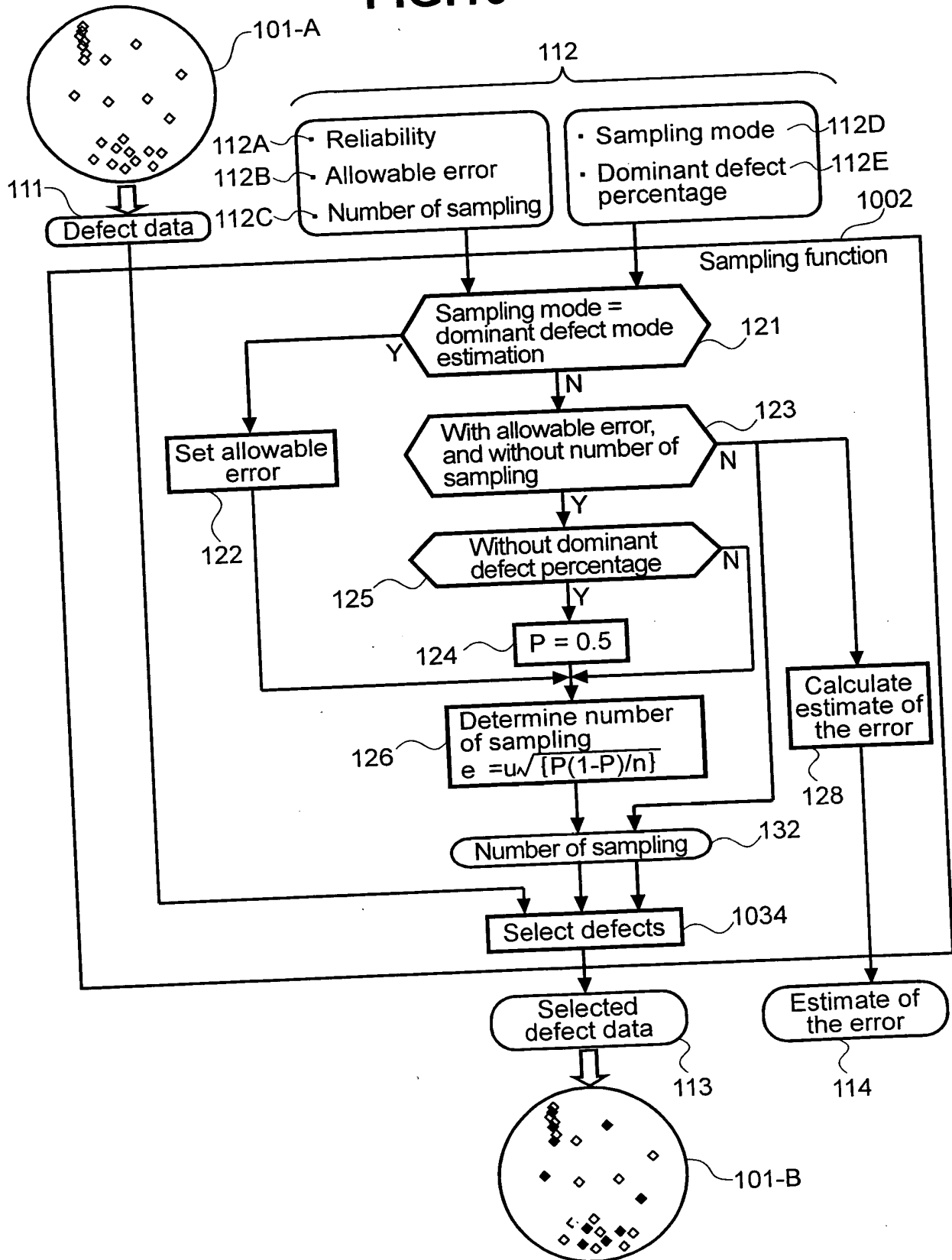


FIG.10



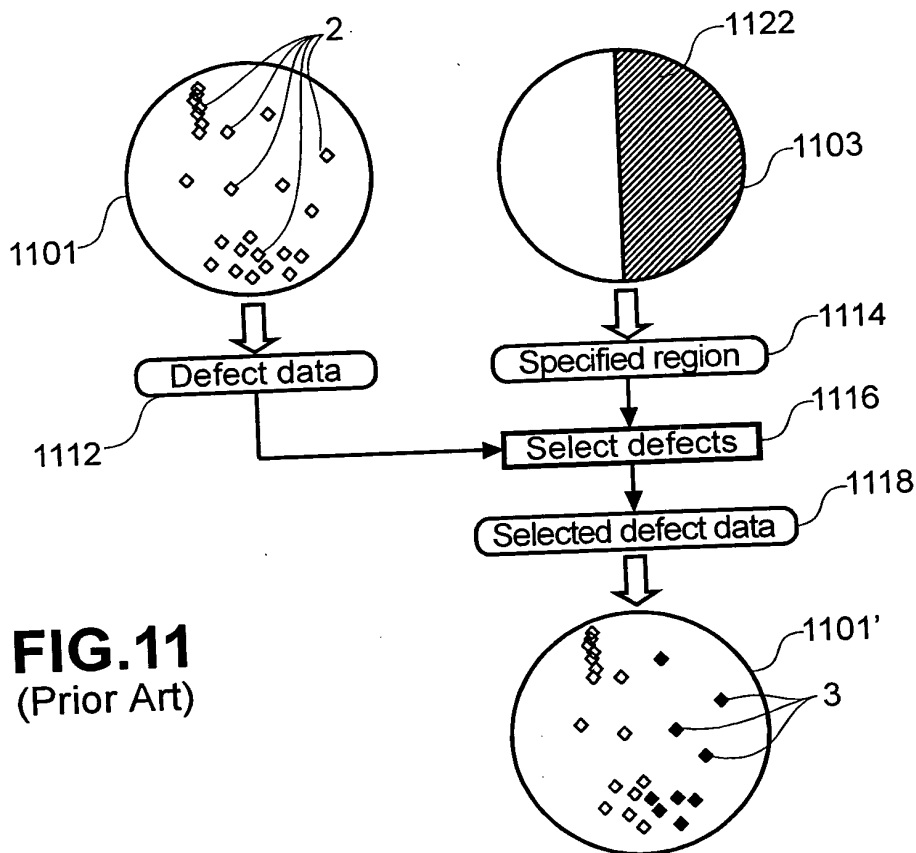


FIG. 11
 (Prior Art)

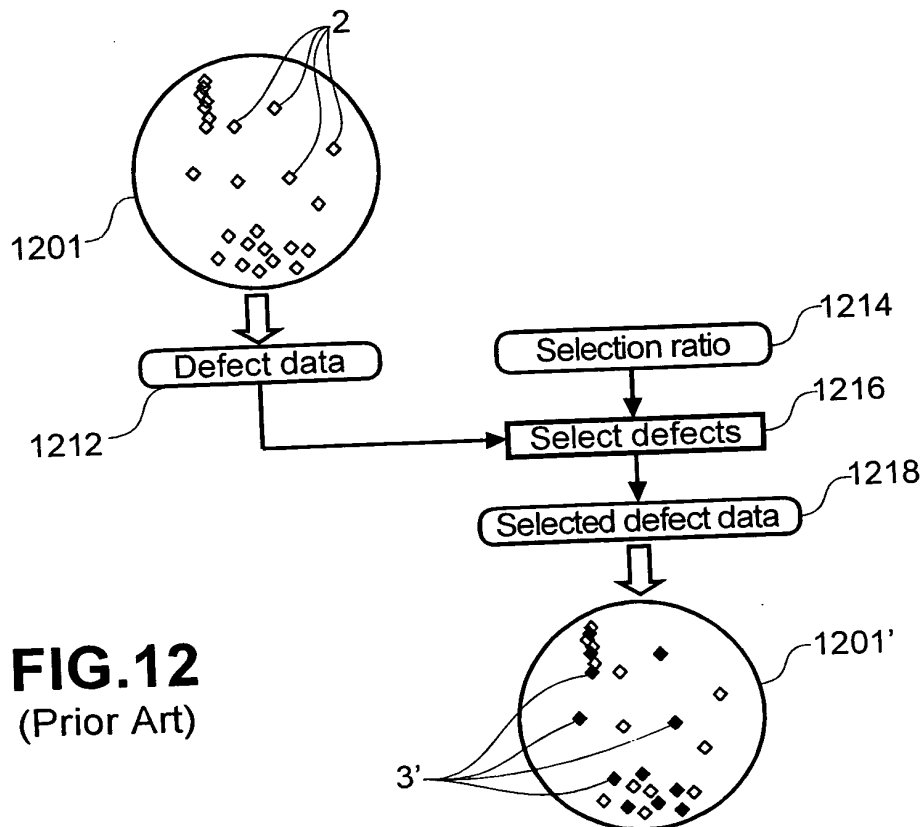


FIG. 12
 (Prior Art)